



Knowledge for Development

Observatory on Science and Technology

Connaissances pour le développement

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3rd International conference on ethics and policy of biometrics and international data sharing

Author:

Introduction: The conference will focus on the research into ethics and policies in the fields of biometrics and data sharing. As the use of biometrics is becoming popular, more concerns on the ethics, privacy and policy implications of biometrics are being raised. The event is organised by the EU-funded RISE ('Rising pan-European and international awareness of biometrics and security ethics') project, which brings together nine institutions from Europe, the United States, China and India. The program committee especially encouraged research papers written from a multi-disciplinary perspective. The general theme is social, cultural and ethical issues in biometric technologies; biometric applications; biometric intelligence; novel applications and risk analysis; security and performance related issues; geographical and technological limitations; challenges and milestones in biometrics; dual use of biometrics; and privacy challenges in biometrics usage.

- **Date(s)**

Monday 04 January 2010 -
Tuesday 05 January 2010

- **Location**

Hong Kong,

- **More information**

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The opinions expressed in the comments and analysis are those of the authors, and do not necessarily reflect the views of CTA.

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